



BiTS™ 2007 Burn-in & Test Socket Workshop

SUMMARY

- 3 Days of Really Hard “Work”
 - 2 Tutorials
 - Invited Speaker
 - 27 Papers
 - Keynote Speaker
 - BiTS EXPO: 58 Exhibitors

The collage includes: a speaker at a podium with a BiTS logo; a large audience seated in a conference hall; an expo booth with staff and visitors; a close-up of electronic components on a test socket; two men reviewing documents; and a large group of people seated at tables in a dining or meeting area.



SUMMARY

AND some time for fun & networking

- An International Murder Mystery: "SPY!"
- Receptions, Breaks, Lunches, Dinners, Networking



**AND WE WERE IN
BEAUTIFUL ARIZONA**





Next Year At BiTS 2008

Seeking

*** Tutorial Proposals ***

*** Panel Proposals ***

*** Speaker Proposals ***

&

*** Abstracts / Papers ***

Contact: Steve Hamren for Abstracts/Papers, Panel & Speakers
Tim Swettlen for Tutorials



BiTS Website

<http://www.bitsworkshop.org>

Coming Soon

M: Mailing

W: Website

- W • [BiTS 2007 Archive \(~April/May 2007\)](#)
- M • [BiTS 2008 Call For Presentations \(~August 2007\)](#)
 - **SHARE YOUR LATEST WORK WITH YOUR COLLEAGUES**
- M • [BiTS 2008 EXPO \(Registration Opens 3Q07\)](#)
- M • [BiTS 2008 Advance Program \(Announced 12/2007\)](#)
- W • [BiTS Blog.....Being Considered](#)
- W • [BiTS-Careers & BiTS-Ads \(2Q2007\)](#)

Your Complete Source For Information About BiTS



BiTS 2007 Feedback

Overall Workshop Evaluation



AWARDS

- Best Data Presented
- Most Inspirational Paper
- Best Presentation, Tutorial in Nature
- Best Presentation / Paper
- AND.....the Special Award.....

Some 'Candidates', but will remain semi-retired for 2007

BiTS 2007
Burn-in & Test Socket Workshop



Special Award
for the
Least Concealed Sales Pitch

The
(Almost) Brilliant Disguise
Award

BiTS 2007
Burn-in & Test Socket Workshop

COMMITTEE

LOCAL ARRANGEMENTS
Valts Treibergs, Chair
Everett Charles Technologies
John Ambrosini
Enplas-Tesco
Owen Prillaman
Yamaichi Electronics

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Antares Advanced Test Technologies

REGISTRATION
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Advantage Specialist

PROGRAM
Steve Hamren
(Sessions Chair)
Micron
Rafiq Hussain
Advanced Micro Devices
Marc Knox
IBM Systems & Tech. Group
John Moore
Texas Instruments
Mike Noel
Freescale
Tim Swettlen
(Tutorials Chair)
Intel

Thank You



Keynote Speaker,
Tutorial Instructors,
Invited Speaker

THANK YOU

Keynote Speaker

Steven R. Appleton
Micron Technology, Inc.

Tutorial Instructors

Steve Arobio
Dynamic Test Solutions

Charles Cohn
TechSearch International

Invited Speaker

Steven B. Strauss
Antares Advanced Test Technologies



Presenters / Authors

THANK YOU

Session 1

Ryan Satrom
Joachim Moerbt
Gert Hohenwarter

Session 2

Michael de Bie
Boris Coto, Rafiq Hussain
Prasanth Ambady
Keith Crowe, Hide Furukawa
Tim Swettlen
Morten Jensen
Val Taruntaev

Session 3

John C. Harkness
John McElreath
Trent Johnson
Jerry Tustaniwskyj

Session 4

Valts Treiberis
Jason Mroczkowski
Eugene Batilo
Ariel Sabello
Che-Yu Li
Frank Bumb
Jack Pereschuk, Nick Langston, Sr.

Session 5

James Zhou
Jiacun (Frank) Zhou
Nick Langston, Sr.
James Zhou, Hongjun Yao
Bill Mack



Presenters / Authors

THANK YOU

Hot Topics Session

Belgacem Haba

David Ovrutsky, Guilian Gao, Vage Oganessian

Norman Armendariz

John Diller

Kiley Beard, Jamie Andes

Session 6

Tushar Mazumder

Andrew Gattuso

Shih-Wei Hsiao

David Shia

Wei-Ming Chi

Byron Gibbs, Kevin McNamara

Session 7

Mark Stenholm

Jeff Sherry

Gerhard Gschwendtberger



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Workshop Guide Advertisers

Exhibitors

Pueblo

P1 RS Tech, Inc.	P5 Boedeker Plastics, Inc.	P9 Phoenix Test Arrays, LLC
P2 E. Jordan Brookes Co., Inc.	P6 RJI Technical Sales	P10 Integrated Test Corp.
P3 Brush Wellman, Inc.	P7 Sensata Technologies, Inc.	P11 Ardent Concepts, Inc.
P4 Enplas Tesco, Inc.	P8 Accutron, Ltd.	P12 RD Chemical Company

Kachina

K1 Synergetix	K4 Yokowo America Corp.	K6 Hyperion Catalysis Int'l., Inc.
K2 Marcel Electronics Int'l.	K5 inTest Silicon Valley Corp.	K7 Matron
K3 Hon Hai Precision (Foxconn)		K8 TDA North America

Alrum

A1 Unitechno USA, Inc.	A14 Professional Plastics	A28 Micronics Japan Co., Ltd.
A2 SEMI	A15 CEIBIS Cody Electronics, Inc.	A29 Victrex USA, Inc.
A3 Micro Control Company	A16 NIK Spring Co., Ltd.	A30 Qualmax, Inc.
A4 E-tec Interconnect, Ltd.	A17 Piper Plastics, Inc.	A31 Antares Adv. Test Tech.
A5 R&D Circuits	A18 Piper Plastics, Inc.	A32 Antares Adv. Test Tech.
A6 Advanced Packaging & SMT	A19 Rika Denshi America, Inc.	A33 Ensinger, Inc.
A7 Johnstech Int'l Corp.	A20 Electroworld	A34 Gryphics, Inc.
A8 P.P.I. -Time Zero, Inc.	A21 Yamaichi Electronics USA	A35 Abrel Products Limited
A9 Nano Measurements	A22 INCAL Technology, Inc.	A36 E. I. Dupont Company
A10 Honeywell	A23 3M	A37 Altanova, Inc.
A11 Protos Electronics	A24 Paricon Technologies Corp.	A38 Ironwood Electronics
A12 Plastronics Socket Co.	A25 Azimuth Electronics, Inc.	A39 Nikon Instruments, Inc.
A13 Everett Charles Technologies	A26 Aehr Test Systems	A40 Dynamic Test Solutions
	A27 Aries Electronics, Inc.	

ATTENDEES

THANK YOU

